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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Patent Application of

James J. Synder et al.

Application No.: 10/672,889

Filed: September 26, 2003

For:

METHOD AND APPARATUS FOR DETERMING THE WAVELENGTH OF

AN INPUT LIGHT BEAM

Group Art Unit: 2877

Examiner: MICHAEL A LYONS

Confirmation No.: 9565

SECOND INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

In accordance with the duty of disclosure as set forth in 37 C.F.R. § 1.56, the accompanying information is being submitted in accordance with 37 C.F.R. §§ 1.97 and 1.98.

Pursuant to 37 C.F.R. § 1.98, a copy of each of the documents cited is enclosed. However, copies of the listed U.S. patents and U.S. patent application publications are not enclosed since it is no longer required according to the July 11, 2003 waiver of the requirement for copies of cited U.S. patents and U.S. patent application publications in national patent applications filed after June 30, 2003 and international applications entering the national stage under 35 U.S.C. § 371 after June 30, 2003.

The documents are being submitted within three (3) months of the filing or entry of the national stage of this application or before the first Office Action on the merits, whichever is later. Since these documents are being filed within the time period set forth in 37 C.F.R. § 1.97(b), no fee or statement is required.

SECOND Information Disclosure Statement
Application No. 10/672,889
Attorney's Docket No. 033806-010
Page 2

To assist the Examiner, the documents are listed on the attached form PTO-1449. It is respectfully requested that an Examiner initialed copy of this form be returned to the undersigned.

By:

Respectfully submitted,

BUCHANAN INGERSOLL PC

Date November 17, 2005

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	Application Number	10/672,889
INFORMATION DISCLOSURE	Filing Date	September 26, 2003
STATEMENT BY APPLICANT	First Named Inventor	James J. Synder et al.
(use as many sheets as necessary	Examiner Name	MICHAEL A LYONS
Sheet 1 of R = 1/40,	Attorney Docket Number	033806-010

	(17 700 st.s.	PATENT DOCUMENTS	
Examiner Initials	Document Number	Kind Codes	Name of Patentee or Applicant of Cited Document	Issue/Publication Date (MM-DD-YYYY)

FOREIGN PATENT DOCUMENTS											
<u> </u>						STATUS					
Examiner Initials	Document Number	Kind Code (if known)	Country	Date of Publication (MM-DD-YYYY)	Translation	Partial Translation	Eng. Lang. Summary	Search Report	IPER	Abstract	Cited in Spec
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NON-PATENT LITERATURE DOCUMENTS					
Examiner Initials	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.				
	Snyder, J.J., "Algorithm for fast digital analysis of interference fringes", <i>Applied Optics 19</i> , 1223 (1980). J.H. Bruing, "Fringe Scanning Interferometers", in <i>Optical Shop Testing</i> , Daniel Malacara, ed. (John Wiley and Sons, New York, 1978) 409-437.				
	Katherine Creath, "Phase-Measurement Interferometry Techniques," in <i>Progress in Optics</i> XXXVI, E. Wolf, ed. (North-Holland, Amsterdam, 1988), 349-393).				

Examiner	Date	
Signature	Considered	
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^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with M.P.E.P. § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant. CA 98807.1